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	Application Number	10/790,967
INFORMATION DISCLOSURE 1000 B	Filing Date	March 2, 2004 .
INFORMATION DISCLOSURE STATEMENT BY APPLICANT CFR 0 9 1000	First Named Inventor	Glenn A. Rinne
	Group Art Unit	1725
(use as many sheets as necessary)	Examiner Name	Michael Aboagye
Sheet 1 of	Attorney Docket Number	9180-10CT

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INFORMATION DISCLOSURE				Filing Date	March 2, 2004		
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luse as n	(use as many sheets as necessary)			Examiner Name	Michael Aboagye		
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Substitute	e form 1449A	/PTO		C	Complete if Known		
•				Application Number	10/790,967		
INFORM	MATION D	ISCLOSUR	E	Filing Date	March 2, 2004		
STATEMENT BY APPLICANT				First Named Inventor	Glenn A. Rinne		
VIAIL		, LIOAII	•	Group Art Unit	1725		
(use as m	(use as many sheets as necessary)			Examiner Name	Michael Aboagye		
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Substitute	e form 1449A/F	ग्र		С	Complete if Known		
				Application Number	10/790,967		
INFOR	MATION DIS	SCLOSURE		Filing Date	March 2, 2004		
	STATEMENT BY APPLICANT			First Named Inventor	Glenn A. Rinne		
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				Application Number	10/790,967		
INFORMATION DISCLOSURE				Filing Date	March 2, 2004		
STATE	STATEMENT BY APPLICANT			First Named Inventor	Glenn A. Rinne		
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INFORMATION DISCLOSURE			E	Filing Date	March 2, 2004	
STATEMENT BY APPLICANT		First Named Inventor	Glenn A. Rinne			
		Group Art Unit	1725			
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Examiner Signature Date Considered 04/21/2006

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Substitute form 1449A/PTO				Complete if Known		
	·			Application Number	10/790,967	
INFORM	MATION D	ISCLOSUR	Ε	Filing Date	March 2, 2004	
STATE	TATEMENT BY APPLICANT		First Named Inventor Group Art Unit	Glenn A. Rinne		
1017.1	TATEMENT BY APPLICANT	1725				
luse as m	(use as many sheets as necessary)				Examiner Name	Michael Aboagye
Sheet	7	of	7	Attorney Docket Number	9180-10CT	

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